

Application/Control No.	Applicant(s)/Patent unde Reexamination	r
10/812,242	STEWARD ET AL.	
Examiner	Art Unit	
Brian Vouna	2810	

	SEARCHED					
Class	Subclass	Date	Examiner			
341	172,150, 161,150, 143	10/19/2005	BY			
505	826 827	10/19/2005	BY			
		-				

INTERFERENCE SEARCHED						
Class	Subclass	Date	Examiner			
341	161	10/19/2005	BY			
(pgpub	only)					

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
EAST (JPO,EPO, Derwent (see atttached) NPL(IEEE,PORTAL)	10/19/2005	ВҮ	
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